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| FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT (USE SEVERAL SHEETS IF NECESSARY) | ATTY. DOCKET NO. MICRON.111C1 | APPLICATION NO. Unknown |
| | APPLICANT Raina, et al. | |
| | FILING DATE Herewith | GROUP 2879 |

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| S.R. | 15 | Young-Chang Joo, et al. 1996. Electromigration in single-crystal aluminum lines pre-damaged by nanoindentation, <i>Materials Research Society Symp. Proc.</i> , 428:225-230. |
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| EXAMINER | Sikha Roy | DATE CONSIDERED | 6/9/04 |
| *EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT. | | | |